
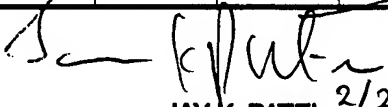
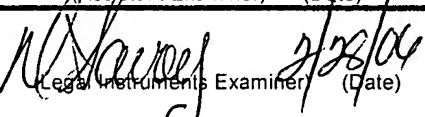


Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/088,694	HAYATA, TOSHIHIRO	
	Examiner	Art Unit	
	Jacob Meek	2637	

ISSUE CLASSIFICATION									
ORIGINAL					CROSS REFERENCE(S)				
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
375		147		375	349				
INTERNATIONAL CLASSIFICATION									
H	0	4	B	1/69					
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				/					
				/					
Jacob Meek 2/24/06 (Assistant Examiner) (Date)					 JAY K. PATEL 2/28/06 SUPERVISORY PATENT EXAMINER (Primary Examiner) (Date)			Total Claims Allowed: 8	
 Legal Instruments Examiner (Date)								O.G. Print Claim(s)	O.G. Print Fig.
								12	2

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant				<input type="checkbox"/> CPA				<input type="checkbox"/> T.D.				<input type="checkbox"/> R.1.47			
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